



EMC COMPLIANCE TEST REPORT

for

EBX FORM FACTOR P IIICPU Board

Trade Name : N/A
Model Number : PCM-9572FV; PCM-9572F
Serial Number : N/A`
Report Number : 000906-E
Date : November 28, 2000
Regulations : See below

Standards	Results (Pass/Fail)
EN 55022: 1994 + A1: 1995 + A2: 1997	PASS
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998	PASS
EN 61000-3-3: 1995	PASS
EN 50082-1: 1997	PASS
- EN 61000-4-2: 1995	PASS
- EN 61000-4-3: 1995	PASS
- ENV 50204 : 1995	PASS
- EN 61000-4-4: 1995	PASS
- EN 61000-4-5: 1995	PASS
- EN 61000-4-6: 1996	PASS
- EN 61000-4-8: 1993	N/A
- EN 61000-4-11: 1994	PASS

Prepared for :

Advantech Co., Ltd.
4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.

Prepared by :



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C&C Laboratory Co., Ltd.**



EC-Declaration of Conformity

For the following equipment:

EBX FORM FACTOR P III CPU Board

(Product Name)

PCM-9572FV; PCM-9572F

(Model Designation / Trade name)

Advantech Co., Ltd..

(Manufacturer Name)

4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City, Taipei Hsien, Taiwan, R.O.C.

(Manufacturer Address)

is herewith confirmed to comply with the requirements set out in the Council Directive on the Approximation of the Laws of the Member States relating to Electromagnetic Compatibility Directive (89/336/EEC, Amended by 92/31/EEC & 93/68/EEC & 98/13/EC), For the evaluation regarding the Electromagnetic Compatibility (89/336/EEC, Amended by 92/31/EEC & 93/68/EEC & 98/13/EC), the following standards are applied:

☒ EN 55022: 1994+A1: 1995+A2: 1997

☒ EN 61000-3-2: 1995+A1: 1998+A2: 1998 ; EN 61000-3-3: 1995

☒ EN50082-1: 1997

EN 61000-4-2: 1995, EN 61000-4-3: 1995, ENV 50204: 1995, EN 61000-4-4: 1995,
EN 61000-4-5: 1995, EN 61000-4-6: 1996, EN 61000-4-11: 1994

The following manufacturer / importer or authorized representative established within the EUT is responsible for this declaration:

(Company Name)

(Company Address)

Person responsible for making this declaration:

(Name, Surname)

(Position / Title)

(Place)

(Date)

(Legal Signature)

Accredited Lab. of NEMKO, A2LA, BSMI
Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission)
NEMKO Authorization #: ELA 124 (for EMC)

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Rev. 00

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VERIFICATION OF COMPLIANCE

Equipment Under Test: EBX FORM FACTOR P III CPU Board
Trade Name: ADVANTECH
Model Number: PCM-9572FV; PCM-9572F
Serial Number: N/A
Applicant: **Advantech Co., Ltd.**
4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.
Manufacturer: **Advantech Co., Ltd.**
4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.
Type of Test: EMC Directive 89/336/EEC for CE Marking
Technical Standards: EN 55022: 1994 + A1: 1995 + A2: 1997
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998; EN 61000-3-3: 1995
EN 50082-1: 1997 (EN 61000-4-2: 1995, EN 61000-4-3: 1995,
ENV 50204: 1995, EN 61000-4-4: 1995,
EN 61000-4-5: 1995, EN 61000-4-6: 1996,
EN 61000-4-11: 1994)
File Number: 000906-E
Date of test: November 23 ~ 25, 2000
Deviation: N/A
Condition of Test Sample: Normal

The above equipment was tested by C&C Laboratory Co., Ltd. for compliance with the requirements set forth in EMC Directive 89/336/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved by Authorized Signatory: Kurt Chen
Kurt Chen / Q.A. Manager



GENERAL INFORMATION

Applicant: **Advantech Co., Ltd.**
4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.

Contact Person: Gary Shih

Manufacturer: **Advantech Co., Ltd.**
4th FL., No. 108-3 Ming-Chuan Road, Hsin-Tien City,
Taipei Hsien, Taiwan, R.O.C.

File Number: 000906-E

Date of Test: November 23 ~ 25, 2000

Equipment Under Test: EBX FORM FACTOR P III CPU Board

Model Number: PCM-9572FV; PCM-9572F

Serial Number: N/A

Technical Standards: EN 55022: 1994 + A1: 1995 + A2: 1997
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998; EN 61000-3-3: 1995
EN 50082-1: 1997 (EN 61000-4-2: 1995, EN 61000-4-3: 1995,
ENV 50204: 1995, EN 61000-4-4: 1995,
EN 61000-4-5: 1995, EN 61000-4-6: 1996,
EN 61000-4-11: 1994)

**Frequency Range
(EN 55022):** 150kHz to 30MHz for Line Conducted Test
30MHz to 1000MHz for Radiated Emission Test

Test Site **C & C LABORATORY CO., LTD.**
No. 15, 14 Lin, Chi Twu Chi, Lu-Chu Hsiang
Taoyuan, Taiwan, R. O. C.



SYSTEM DESCRIPTION

EUT Test Program:

1. The EUT was installed in a host PC, then EMI test program (file name: EMCTEST. EXE) was loaded and executed in "Window" mode.
2. Data was sent to VGA Monitor or TV and filling the screen with upper case of "H" patterns.
3. Test program sequentially exercised all related I/O's and accessories of EUT, and sent "H" patterns to all applicable output ports of EUT.
4. The host PC was also connected to a Notebook at a remote site and data was transmitted between the host PC and Notebook via a LAN Cable.
5. Repeat 2 to 4. Test program is self-repeating throughout the test.

PRODUCT INFORMATION

Housing Type:	Metal Case	
EUT Power Rating:	88-264VAC; 0.9~1.8A; 47/63Hz	
AC Power during test	230VAC/50Hz to power supply	
AC Power Cord Type:	Unshielded, 1.8m. (Detachable)	
Housing Model:	MBPC-300	
Power Supply Manufacturer:	ADVANTECH	
Power Supply Model Number:	PS-55A	
Power Supply Power Rating:	I/P:88-264VAC,47/63Hz,0.9~1.8A	
OSC/Clock Frequencies :	66 MHz	
CPU Manufacture:	Intel	Type: Celeron 500MHz

I/O Port of EUT

I/O PORT TYPES	Q'TY	TESTED WITH
1).Parallel Port	1	1
2).Serial Port	3	3
3).PS/2 Keyboard Port/Mouse port	2	2
4).VIDEO	1	1
5).Microphone Port	1	1
6).Line-in Port	1	1
7).Line-out Port	1	1
8).USB Port	2	2
9).SPEAKER-OUT	1	1
10).TV-OUT	1	1
11).LAN	1	1

Note: The difference of Mode No: PCM-9572FV and PCM-9572F is PCM-9572FV have include one TV-OUT port, but PCM-9572F haven't.

SUPPORT EQUIPMENT

No.	Equipment	Model #	Serial #	FCC ID	Trade Name	Data Cable	Power Cord
1.	Monitor	D2827A	KR92316215	C5F7NFCMC1518X	HP	Shielded, 1.8m	Unshielded, 1.8m
2.	Printer	C2642A	MY8261C964	B94C2642X	HP	Shielded, 1.8m	AC I/P: Unshielded, 0.9m DC O/P: Unshielded, 1.9m
3.	Modem	2400	94-364-176276	DK467GSM24	Computer Peripherals	Shielded, 1.8m	Unshielded, 1.5m
4.	PS/2 Keyboard	SK-2502C	M99043551	FCC DoC	HP	Shielded, 1.8m	N/A
5.	PS/2 convert to com Mouse	M-CAA43	LZE02802014 LZE02821285	DZL211153	Logitech	Shielded, 1.8m	N/A
6.	PS/2 Mouse	M-S34	LZA82701234	DZL211029	Logitech	Shielded, 1.8m	N/A
7.	USB Mouse	SL-A 799111	U0-1	E6QMOUSE X31	JOW DAIN	Shielded, 1.4m	N/A
8.	USB Mouse	M-BB48	LZE93050164	FCC DoC	Logitech	Shielded, 1.8m	N/A
9.	Multimedia Headset	SX-M	A5-4	N/A	TOKYO	Unshielded, 1.8m	N/A
10.	Multimedia Headset	SX-M	A5-5	N/A	TOKYO	Unshielded, 1.8m	N/A
11.	Walkman	YX-328	W1	N/A	YING-KO	Unshielded, 1.8m	N/A
12.	TV	21S3	70332865	N/A	Toshiba	N/A	Unshielded, 1.8m
13.	Notebook PC (Remote)	365	TZ30518	DoC	Acer	Shielded, 10m	AC I/P: Unshielded, 0.8m DC O/P: Unshielded, 1.2m

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.



TEST FACILITY

- Location:** No. 15, 14 Line, Chin Twu Chi, Lu Chu Hsiang, Taoyuan, Taiwan, R.O.C.
- Description:** There are four 3/10m open area test sites and three line conducted labs for final test.
The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4: 1992 and CISPR 22/EN 55022 requirements.
- Site Filing:** A site description is on file with the Federal Communications Commission, 7435 Oakland Mills Road, Columbia, MD 21046.

Registration also was made with Voluntary Control Council for Interference (VCCI).
- Site Accreditation:** Accredited by NEMKO (Authorization #: ELA 124) for EMC & A2LA (Certificate #: 824.01) for Emission

Also accredited by BSMI for the product category of Information Technology Equipment.
- Instrument Tolerance:** All measuring equipment is in accord with ANSI C63.4 and CISPR 22 requirements that meet industry regulatory agency and accreditation agency requirement.

Ground Plane: Two conductive reference ground planes were used during the Line Conducted Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.

Site # 1 & # 3 Line Conducted Test Site: Vertical ground plane (2.2m x 2.2m)
Horizontal ground plane (2.5m x 2.5m)

Site # 4 Line Conducted Test Site: At Shielding Room



TEST EQUIPMENT LIST

Instrumentation: The following list contains equipment used at C & C Laboratory, Co., Ltd. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2-1988 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 10kHz to 1.0 / 2.0 GHz.

Equipment used during the tests:

Open Area Test Site: ☐ # 1 ; ☐ # 2 ; ☐ # 3 ; ☒ # 4

Open Area Test Site # 1					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Q.P Adaptor	HP	85650A	2811A01399	05/05/2000	05/04/2001
RF Pre-selector	HP	85685A	2947A01064	05/05/2000	05/04/2001
Spectrum Analyzer	HP	8568B	3001A05004	05/05/2000	05/04/2001
S.P.A Display	HP	8568B	3014A18846	05/05/2000	05/04/2001
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001
Bilog Antenna	CHASE	CBL6112A	2309	02/13/2000	02/12/2001
Turn Table	EMCO	2081-1.21	N/A	N.C.R	N.C.R
Antenna Tower	EMCO	2075-2	9707-2604	N.C.R	N.C.R
Controller	EMCO	2090	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M54367	N.C.R	N.C.R
Site NSA	C&C	N/A	N/A	11/05/2000	11/04/2001

Open Area Test Site # 2					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261A	N/A	03/08/2000	03/07/2001
Pre-Amplifier	HP	8447F	2944A03748	11/10/2000	11/09/2001
EMI Test Receiver	R&S	ESVS10	834468/006	03/24/2000	03/23/2001
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001
Bilog Antenna	CHASE	CBL 6112B	2635	10/23/2000	10/22/2001
Turn Table	Chance Most	CM-T003-1	T807-6	N.C.R	N.C.R
Antenna Tower	Chance Most	CM-A003-1	A807-6	N.C.R	N.C.R
Controller	Chance Most	N/A	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M76890	N.C.R	N.C.R
Site NSA	C&C Lab.	N/A	N/A	11/11/2000	11/10/2001



Open Area Test Site # 3					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261A	21720279	08/15/2000	08/14/2001
Pre-Amplifier	HP	8447D	2944A09173	02/01/2000	01/31/2001
EMI Test Receiver	R&S	ESVS20	838804/004	12/24/1999	12/23/2000
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001
Bilog Antenna	CHASE	CBL6112A	2179	12/01/2000	11/30/2001
Turn Table	EMCO	2081-1.21	9709-1885	N.C.R	N.C.R
Antenna Tower	EMCO	2075-2	9707-2060	N.C.R	N.C.R
Controller	EMCO	2090	9709-1256	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M53867	N.C.R	N.C.R
Site NSA	C&C	N/A	N/A	01/29/2000	01/28/2001

Open Area Test Site # 4					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3261C	81720301	09/02/2000	09/01/2001
EMI Test Receiver	R&S	ESVS10	846285/016	12/17/1999	12/16/2000
Pre-Amplifier	HP	8447	2727A06240	10/17/2000	10/16/2001
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001
Bilog Antenna	CHASE	CBL 6112B	2462	01/13/2000	01/12/2001
Turn Table	Chance most	N/A	N/A	N.C.R	N.C.R
Antenna Tower	Chance most	N/A	N/A	N.C.R	N.C.R
Controller	Chance most	N/A	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M51067	N.C.R	N.C.R
Site NSA	C&C Lab.	N/A	N/A	12/26/1999	12/25/2000

Conducted Emission Test Site: # 4

Conducted Emission Test Site # 4					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
EMI Test Receiver	R&S	ESHS10	843743/015	12/10/1999	12/09/2000
LISN	EMCO	3825/2	9003/1382	01/10/2000	01/09/2001
LISN	EMCO	3825/2	9003-1628	07/12/2000	07/11/2001

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.



TEST EQUIPMENT LIST

For Power Harmonic & Voltage Fluctuation/Flicker Measurement:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH Harmonic & Flicker Tester	PHF 555	080 419-25	Oct. 16, 2000	Oct. 15, 2001

For ESD test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY/TRENCH ESD Generator	PESD 1600	H710203	Sep. 02, 2000	Sep. 01, 2001

For Radiated Electromagnetic Field immunity Measurement:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Maconi /Signal Generator	2022D	119246/003	Aug. 21, 2000	Aug. 20, 2001
M2S / Power Amplifier	A00181/1000	9801-112	N/A	N/A
M2S / Power Amplifier	AC8113/800-250A	9801-179	N/A	N/A
Wandel & Goltormann/ EM-Radiation Meter	EMR-30	L-0013	Feb. 25, 2000	Feb. 24, 2001
EMCO Power Antenna	93141	9712-1083	N/A	N/A

For Fast Transients/Burst test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Fast Transients/Burst Generator	PEFT-JUNIOR	583 333-117	Aug. 21, 2000	Aug. 20, 2001

For CS test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Maconi /Signal Generator	2022D	119246/003	Aug. 21, 2000	Aug. 20, 2001
MEB / CDN M3	M3	3683	Sep. 11, 2000	Sep. 10, 2001
M2S / Power Amplifier	A00181/1000	9801-112	N/A	N/A

For Surge Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Surge Tester	PSURGE 4010	583 334-71	Sep. 01, 2000	Aug. 31, 2001

For Power Frequency Magnetic Field Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
F.W.BELL/ TRIAX ELF Magnetic Field Meter	4090	9711	Oct, 20,2000	Oct.19, 2001
HAEFELY TRENCH/ Magnetic Field Tester	MAG 100.1	080 938-01	N/A	N/A

For Voltage Dips/Short Interruption and Voltage Variation Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Dips/Interruption and Variations Simulator	PLINE 1610	080 344-05	Jan. 31, 2000	Jan. 30, 2001



SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)

MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received AC power through a Line Impedance Stabilization Network (LISN) which supplied power source of 230VAC/50Hz and was grounded to the ground plane.
- 5) All support equipment received power from a second LISN supplying power of 110VAC/60Hz, if any.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7) Analyzer scanned from 150kHz to 30MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test mode(s) were scanned during the preliminary test:

Mode(s): (Customer defines)

1. 1024	x	768	+ VGA ON + TV OFF
2. 800	x	600	+ VGA ON + TV OFF
3. 640	x	480	+ VGA ON + TV OFF
4. 640	x	480	+ VGA OFF+ TV ON

- 10) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 1. 1024 x 768 + VGA ON + TV OFF

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

MEASUREMENT PROCEDURE (FINAL LINE CONDUCTED EMISSION TEST)

- 1) EUT and support equipment was set up on the test bench as per step 10 of the preliminary test.
- 2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less -2dB to the A.V. limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- 3) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. MHz	Q.P. Raw dBuV	Average Raw dBuV	Q.P. Limit dBuV	Average Limit dBuV	Q.P. Margin dB	Average Margin dB	Note
x.xx	43.95	---	56	46	-12.05	-2.05	L 1

Freq.	= Emission frequency in MHz
Raw dBuV	= Uncorrected Analyzer/Receiver reading
Limit dBuV	= Limit stated in standard
Margin dB	= Reading in reference to limit
Note	= Current carrying line of reading
“---”	= The emission level complied with the Average limits, with at least 2 dB margin, so no further recheck.

LINE CONDUCTED EMISSION LIMIT

Frequency	Maximum RF Line Voltage	
	Q.P.	AVERAGE
150kHz-500kHz	66-56dBuV	56-46dBuV
500kHz-5MHz	56dBuV	46dBuV
5MHz-30MHz	60dBuV	50dBuV

Note: The lower limit shall apply at the transition frequency.



MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received 230VAC/50Hz power source from the outlet socket under the turntable. All support equipment received 110VAC/60Hz power from another socket under the turntable, if any.
- 5) The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the analyzer via a cable and at times a pre-amplifier would be used.
- 6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 7) The following test mode(s) were scanned during the preliminary test:

Mode(s): (Customer defines)

1	1024	x	768	+ VGA ON + TV OFF
2.	800	x	600	+ VGA ON + TV OFF
3.	640	x	480	+ VGA ON + TV OFF
4.	640	x	480	+ VGA OFF+ TV ON

- 8) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 1. 1024 x 768 + VGA ON + TV OFF

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.



MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 8 of the preliminary test.
- 2) The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 3) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
xx.xx	14.0	11.2	26.2	30	-3.8

Freq.	= Emission frequency in MHz
Raw Data (dBuV/m)	= Uncorrected Analyzer / Receiver reading
Corr. Factor (dB)	= Correction factors of antenna factor and cable loss
Emiss. Level	= Raw reading converted to dBuV and CF added
Limit dBuV/m	= Limit stated in standard
Margin dB	= Reading in reference to limit

RADIATED EMISSION LIMIT

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBu V/m/ Q.P.)
30-230	10	30
230-1000	10	37

Note: The lower limit shall apply at the transition frequency.

BLOCK DIAGRAM OF TEST SETUP

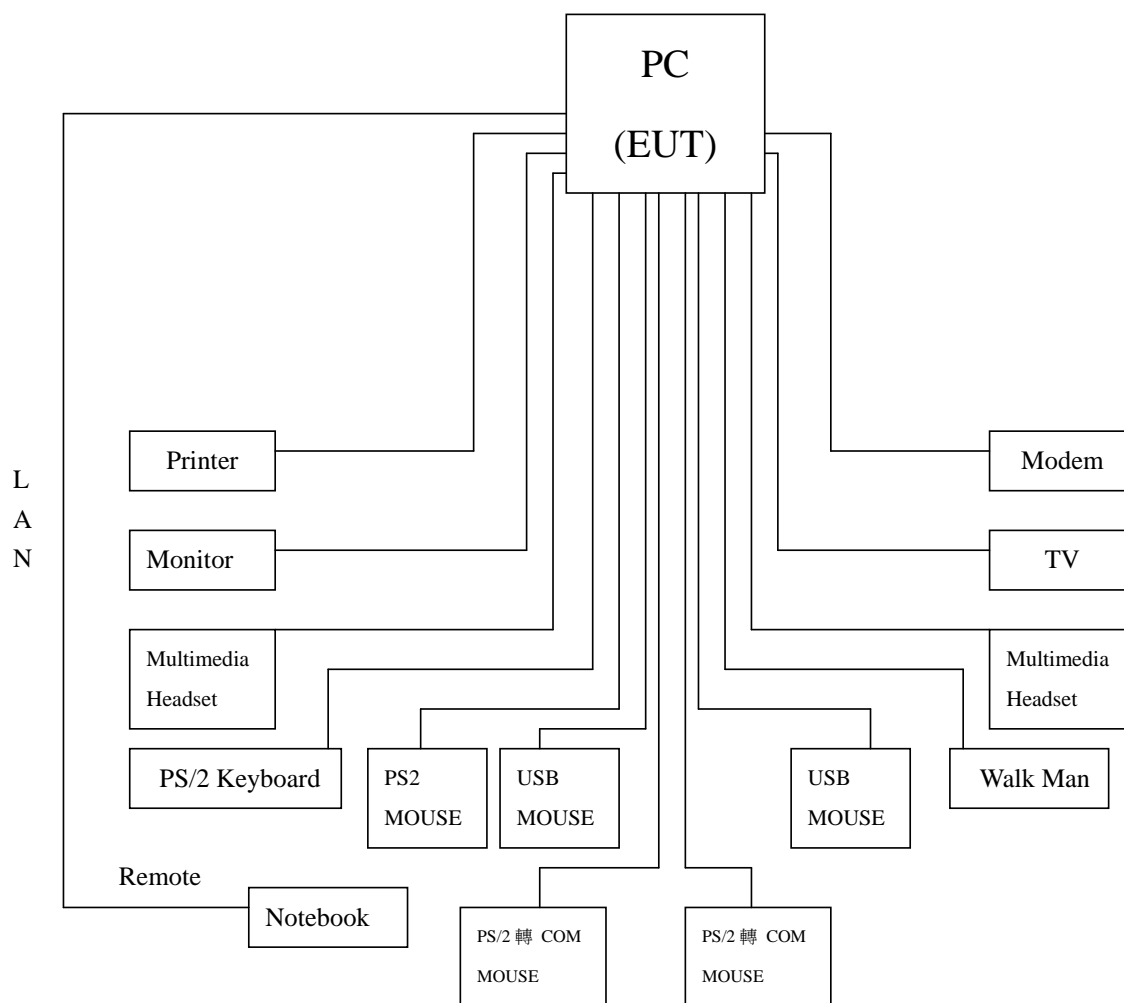
SYSTEM DIAGRAM OF CONNECTIONS BETWEEN EUT AND SIMULATORS

EUT: CPU Board

Trade Name: N/A

Model Number: PCM-9572FV

Power Cord: Unshielded, 1.8m



SUMMARY DATA (LINE CONDUCTED TEST)

Model Number: PCM-9572FV

Location: Site # 4

Tested by: Jack Chen

Test Mode: Mode 1

Test Results: Passed

Temperature: 22°C

Humidity: 67%RH

(The chart below shows the highest readings taken from the final data)

FREQ MHz	Q.P. Raw dBuV	AVG Raw dBuV	Q.P. Limit dBuV	AVG Limit dBuV	Q.P. Margin dB	AVG Margin dB	NOTE
0.211	44.6	---	63.10	53.10	-18.50	---	L1
7.896	40.5	---	60.00	50.00	-19.50	---	L1
9.284	39.7	---	60.00	50.00	-20.30	---	L1
10.884	42.5	---	60.00	50.00	-17.50	---	L1
15.372	40.1	---	60.00	50.00	-19.90	---	L1
16.341	41.4	---	60.00	50.00	-18.60	---	L1
1.524	35.9	---	56.00	46.00	-19.60	---	N
7.139	36.5	---	60.00	50.00	-23.50	---	N
9.772	37.8	---	60.00	50.00	-22.20	---	N
10.884	40.9	---	60.00	50.00	-19.10	---	N
12.196	36.1	---	60.00	50.00	-23.90	---	N
16.322	40.0	---	60.00	50.00	-20.00	---	N

L1 = Line One (Hot side) / L2 = Line Two (Neutral side)

****NOTE: “---” denotes the emission level was less –2 dB to the Average limit, so no re-check anymore.**



SUMMARY DATA (RADIATED EMISSION TEST)

Model Number: PCM-9572FV	Location: Site # 4
Tested by: Jack Chen	
Test Mode: Mode 1	Polar: Vertical -- 10m
Detector Function: Quasi-Peak	Test Results: Passed
Temperature: 24°C	Humidity: 69%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
55.64	18.7	7.8	26.5	30.0	-3.5
79.32	18.5	6.8	25.3	30.0	-4.7
120.13	12.6	14.9	27.5	30.0	-2.5
168.12	13.1	10.9	24.0	30.0	-6.0
501.34	14.0	20.0	34.0	37.0	-3.0
698.40	9.2	23.1	32.3	37.0	-4.7



SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: PCM-9572FV	Location: Site # 4
Tested by: Jack Chen	
Test Mode: Mode 1	Polar: Horizontal -- 10m
Detector Function: Quasi-Peak	Test Results: Passed
Temperature: 24 ⁰ C	Humidity: 69%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
80.10	19.1	6.9	26.0	30.0	-4.0
120.32	12.6	14.9	27.5	30.0	-2.5
144.10	14.6	11.9	26.5	30.0	-3.5
168.15	15.6	10.9	26.5	30.0	-3.5
308.60	17.9	15.6	33.5	37.0	-3.5
502.13	13.8	20.0	33.8	37.0	-3.2

SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION/FLICKER)

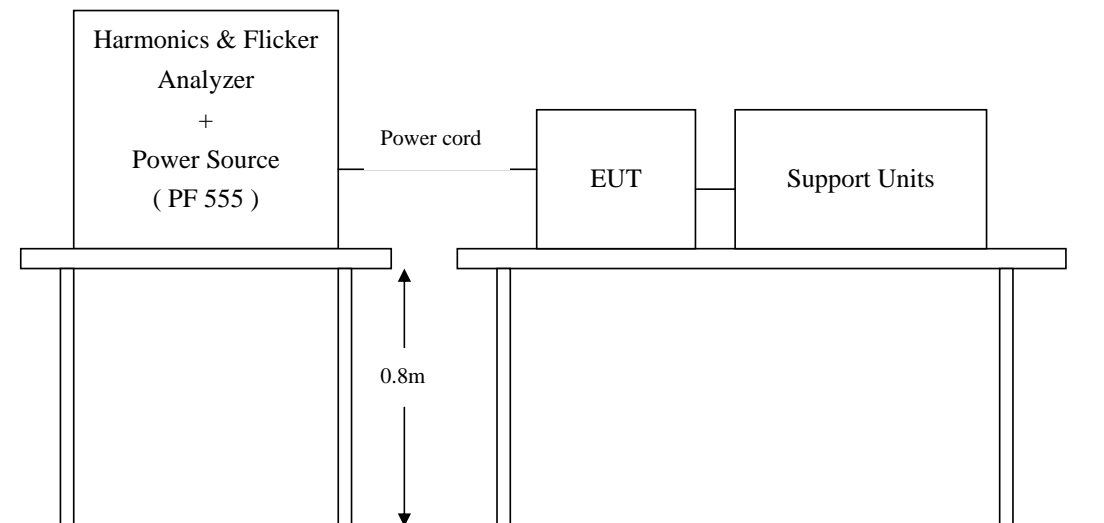
POWER HARMONICS MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-2 (1995+A1: 1998+A2: 1998)
Limits : ☒ Class A, ☐ Class D
Tested by : Jack Chen
Temperature : 24⁰C
Humidity : 48%
Special Wave Shape : Met
Deviation : N/A

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-3 (1995)
Limits : §5 of EN 61000-3-3
Tested by : Jack Chen
Temperature : 24⁰C
Humidity : 48%

Block Diagram of Test Setup:



Result:

Please see the attached test data.



EN 61000-3-2 TEST REPORT 2000/11/24 10:40 AM

Unit: Pentium III

Serial No.: PCM-9572F

Remarks: Temp: 24 °C Humidity: 48 %

Operator: JACK CHEN
=====

TEST SETUP

Test Freq.:	50.00 Hz.	Test Voltage:	230.0 vac
Waveform :	SINE	Test Time:	2.5 min.
Classification :	CLASS A	Test Type:	STEADY-STATE

Prog. Zo Enabled: YES Prog. Zo: 0.000

Motor Driven with Phase Angle Control: NO
Impedance selected: DIRECT

Synthetic R+L Enabled: NO
Resistance: 0.380 Ohms Inductance: 460.000 uH

MAX.WATTS:37.5W



TEST DATA

Result: PASS

Harmonic Current Results

Hn	AMPS	LO Limit	HI Limit	Result
0	0.000	0.000	0.000	PASS
1	0.171	NaN	NaN	PASS
2	0.007	1.080	1.080	PASS
3	0.150	2.300	2.300	PASS
4	0.009	0.430	0.430	PASS
5	0.136	1.140	1.140	PASS
6	0.008	0.300	0.300	PASS
7	0.124	0.770	0.770	PASS
8	0.007	0.230	0.230	PASS
9	0.108	0.400	0.400	PASS
10	0.005	0.184	0.184	PASS
11	0.090	0.330	0.330	PASS
12	0.004	0.153	0.153	PASS
13	0.071	0.210	0.210	PASS
14	0.004	0.131	0.131	PASS
15	0.054	0.150	0.150	PASS
16	0.003	0.115	0.115	PASS
17	0.038	0.132	0.132	PASS
18	0.003	0.102	0.102	PASS
19	0.025	0.118	0.118	PASS
20	0.003	0.092	0.092	PASS
21	0.015	0.107	0.107	PASS



22	0.002	0.084	0.084	PASS
23	0.007	0.098	0.098	PASS
24	0.002	0.077	0.077	PASS
25	0.004	0.090	0.090	PASS
26	0.002	0.071	0.071	PASS
27	0.006	0.083	0.083	PASS
28	0.001	0.066	0.066	PASS
29	0.007	0.078	0.078	PASS
30	0.001	0.061	0.061	PASS
31	0.007	0.073	0.073	PASS
32	0.001	0.058	0.058	PASS
33	0.006	0.068	0.068	PASS
34	0.001	0.054	0.054	PASS
35	0.004	0.064	0.064	PASS
36	0.001	0.051	0.051	PASS
37	0.003	0.061	0.061	PASS
38	0.000	0.048	0.048	PASS
39	0.002	0.058	0.058	PASS
40	0.000	0.046	0.046	PASS



EN 61000-3-3 TEST REPORT 2000/11/24 10:56 AM

Unit: 586 CPU BOARD

Serial No.: PCM-9572

Remarks: Temp: 24 °C Humidity: 48 %

Operator: JACK CHEN

=====

TEST SETUP

Test Freq.: 50.00 Hz. Test Voltage: 230.0 vac

Waveform : SINE

Test Time: 10.0 min. Tshort: 10.0 min.

Prog. Zo Enabled: YES Prog. Zo: 0.000

Voltage Change less than once per Hour: NO

Impedance selected: DIRECT

Synthetic R+L Enabled: NO

Resistance: 0.380 Ohms Inductance: 460.000 uH



TEST DATA

Result: PASS

	EUT Data	Limit	Result	Test Enabled
Pst max	0.010	1.00	PASS	true
Plt max	0.010	0.65	PASS	true
dc %	0.00	3.00	PASS	true
dmax %	0.00	4.00	PASS	true
d(t) sec.	0.00	0.20	PASS	true

Power Source Data

Source Pst max	0.020	0.400	PASS	true
% THD	0.03	3.00	PASS	true

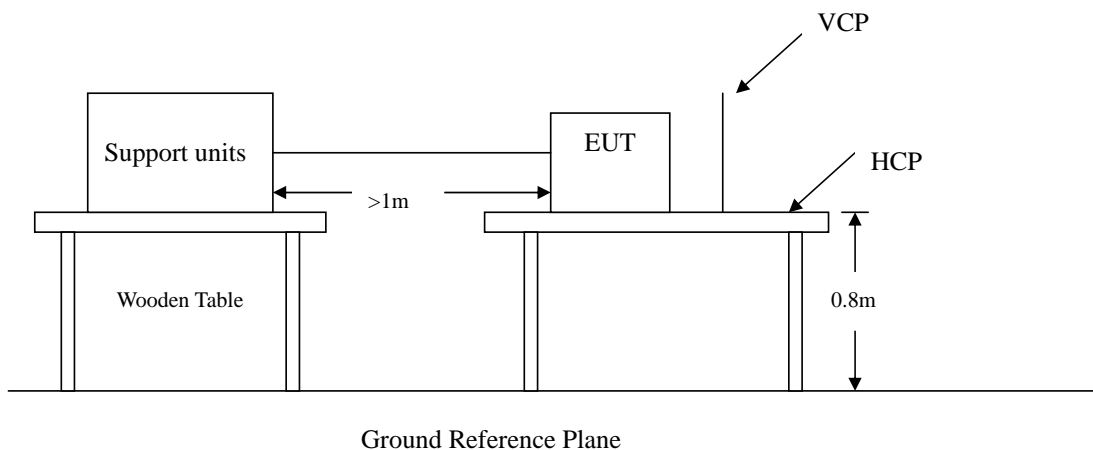
SECTION 3 EN 61000-4-2 (ELECTROSTATIC DISCHARGE)

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure
Basic Standard : EN 61000-4-2
Requirements : ± 8 kV (Air Discharge)
 ± 4 kV (Contact Discharge)
 ± 4 kV (Indirect Discharge)
Performance Criteria : B (Standard require)
Tested by : Jack Chen
Temperature/Humidity: 26°C /45%

Block Diagram of Test Setup:

(The 470 k ohm resistors are installed per standard requirement)



Test Procedure:

1. The Host PC (included EUT) was located 0.1 m minimum from all side of the HCP.
2. The support units were located 1 m minimum away from the Host PC (included EUT).
3. A scroll 'H' test program was loaded and executed in Windows mode.
4. Host PC (included EUT) sent above message to Monitor and related peripherals through the test.
5. Selecting appropriate points of EUT for Contact/Air discharge and put a mark on EUT to show tested points.
6. The following test condition was followed during the tests.

The electrostatic discharges were applied as follows:

Amount of Discharges	Voltage	Coupling	Result (Pass/Fail)
≥ 10/Point	±8kV	Air Discharge	Pass
≥ 10/Point	±4kV	Contact Discharge	Pass
≥ 10/Point	±4kV	Indirect Discharge HCP	Pass
≥ 10/Point	±4kV	Indirect Discharge VCP (Front)	Pass
≥ 10/Point	±4kV	Indirect Discharge VCP (Left)	Pass
≥ 10/Point	±4kV	Indirect Discharge VCP (Back)	Pass
≥ 10/Point	±4kV	Indirect Discharge VCP (Right)	Pass

**** The tested points to EUT, please refer to attached pages.**

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS** ☐ **FAILED**

Observation: No any function degraded during the tests.

The Tested Points of EUT



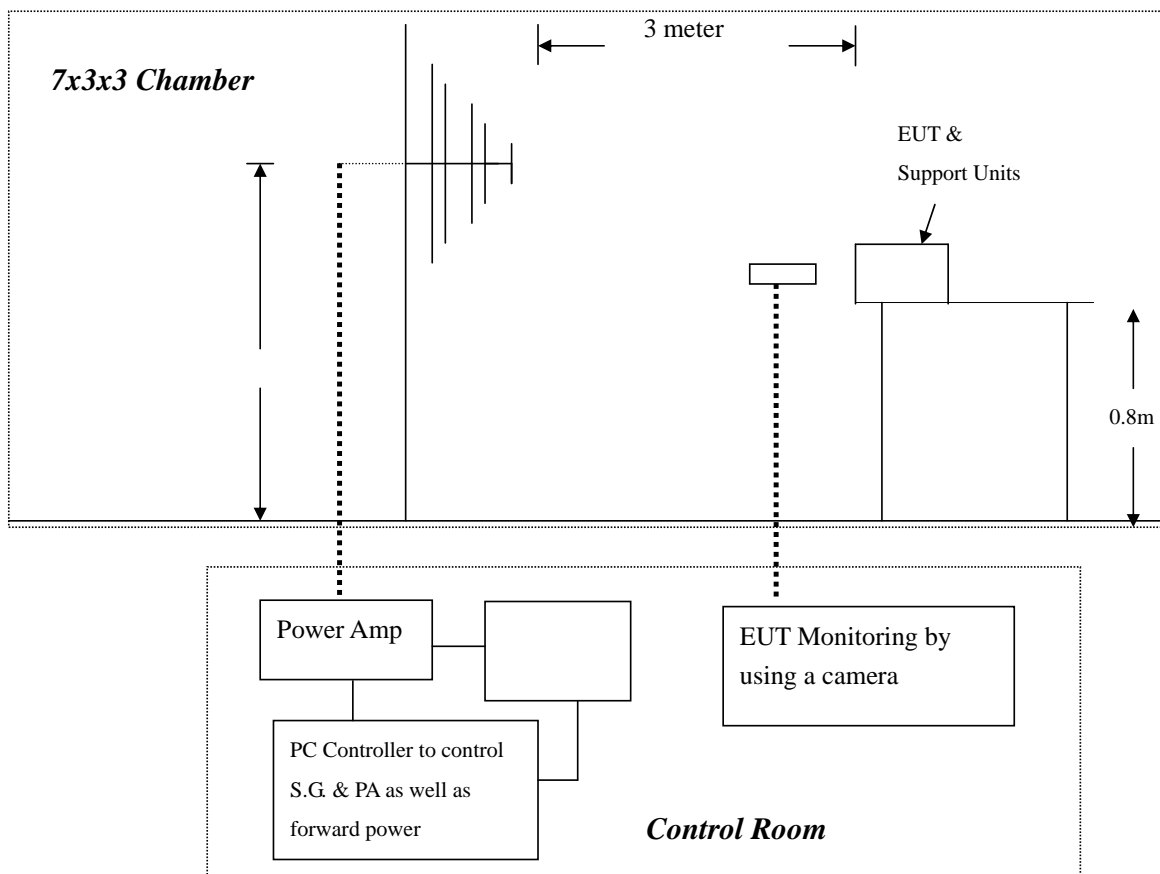


SECTION 4 EN 61000-4-3 & EN 50204 (RADIATED ELECTROMAGNETIC FIELD)

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port : Enclosure
Basic Standard : EN 61000-4-3 & ENV 50204
Requirements : 3 V/m / with 80% AM. 1kHz Modulation. (EN 61000-4-3)
with 200Hz \pm 1% modulation (ENV 50204)
Performance Criteria : A (Standard require)
Tested by : Jack Chen
Temperature : 25°C
Humidity : 59%

Block Diagram of Test Setup:



Test Procedure:

1. The Host PC (included EUT) and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.
2. Adjusting the cables to be exposed to the electromagnetic field as possible.
3. Performing a Radiated Emission Scan in range of 30 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
4. A 'H' messages were displayed on Screen of Monitor.
5. Adjusting the monitoring camera to monitor the 'H' message as clear as possible.
6. Setting the testing parameters of RS test software per EN 61000-4-3.
7. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
8. Recording the test result in following table.
9. Changing the Host PC (included EUT) to the other side and repeat step 3 to 7, until 4 sides of EUT were verified.
10. For ENV 50204 tested at 895, 900, 905 MHz individually and keep same set up as EN 61000-4-3 testing.

Test conditions:

Frequency Range : 80MHz-1000MHz for EN 61000-4-3, 900 MHz \pm 5MHz for ENV 50204

Frequency Step : 1% of fundamental for EN 61000-4-3

Dwell Time : 3 sec

EN 61000-4-3

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	3V	Yes	H	0	Pass
80-1000	3V	Yes	V	0	Pass
80-1000	3V	Yes	H	90	Pass
80-1000	3V	Yes	V	90	Pass
80-1000	3V	Yes	H	180	Pass
80-1000	3V	Yes	V	180	Pass
80-1000	3V	Yes	H	270	Pass
80-1000	3V	Yes	V	270	Pass

ENV 50204

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
900 \pm 5	3V	Yes	H	0	Pass
900 \pm 5	3V	Yes	V	0	Pass
900 \pm 5	3V	Yes	H	90	Pass
900 \pm 5	3V	Yes	V	90	Pass
900 \pm 5	3V	Yes	H	180	Pass
900 \pm 5	3V	Yes	V	180	Pass
900 \pm 5	3V	Yes	H	270	Pass
900 \pm 5	3V	Yes	V	270	Pass



Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS**

☐ **FAILED**

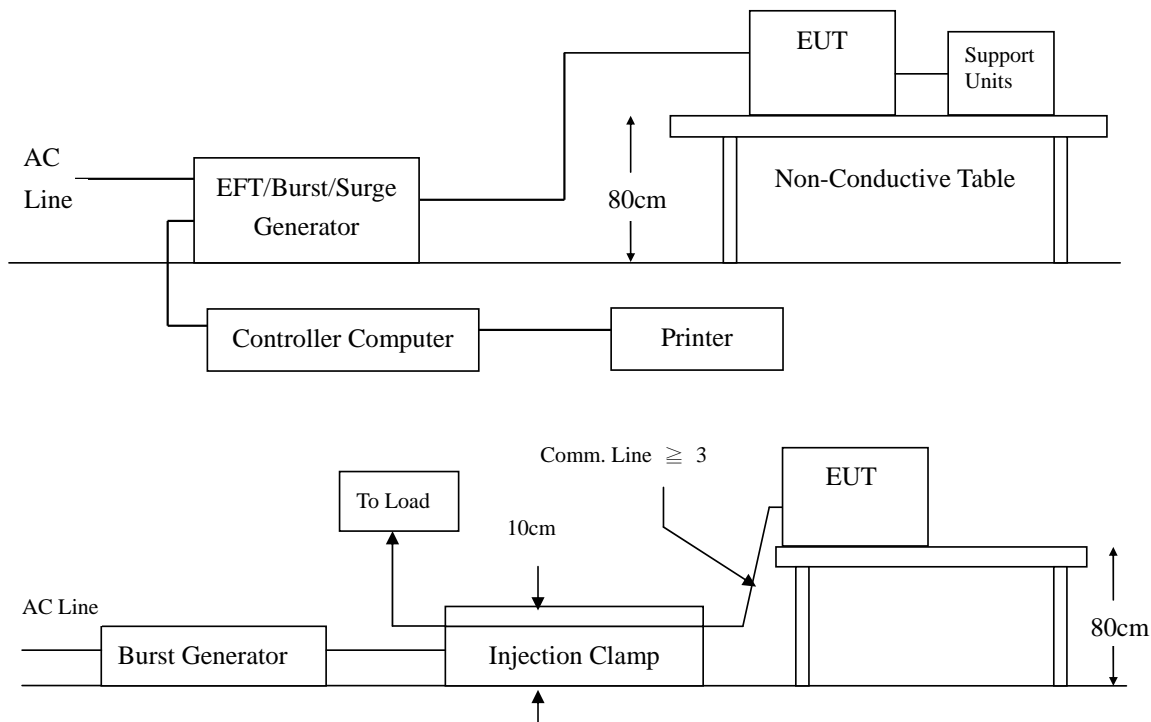
Observation: No any function degraded during the tests.

SECTION 5 EN 61000-4-4 (FAST TRANSIENTS/BURST)

FAST TRANSIENTS/BURST IMMUNITY TEST

Port	: On Power Supply Ports and Data Cable
Basic Standard	: EN 61000-4-4
Requirements	: $\pm 1\text{kV}$ for Power Supply Line $\pm 0.5\text{kV}$ for Data Cable
Performance Criteria	: B (Standard require)
Tested by	: Jack Chen
Temperature	: 26°C
Humidity	: 45 %

Block Diagram of Test Setup:



Test Procedure:

1. The Host PC (included EUT) and support units were located on a wooden table 0.8 m away from ground reference plane.
2. A test program was loaded and executed in Windows mode.
3. The data was sent to the screen of Monitor and filling the screen with upper case of "H" patterns.
4. The test program exercised related support units sequentially.
5. Repeating step 3 to 4 through the test.
6. Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5kHz

Tr/Th: 5/50ns

Burst Duration: 15ms

Burst Period: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L1	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L1 + N	± 1	Direct	Pass
L1 + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L1 + N + PE	± 1	Direct	Pass
LAN	± 1	Clamp	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS** ☐ **FAILED**

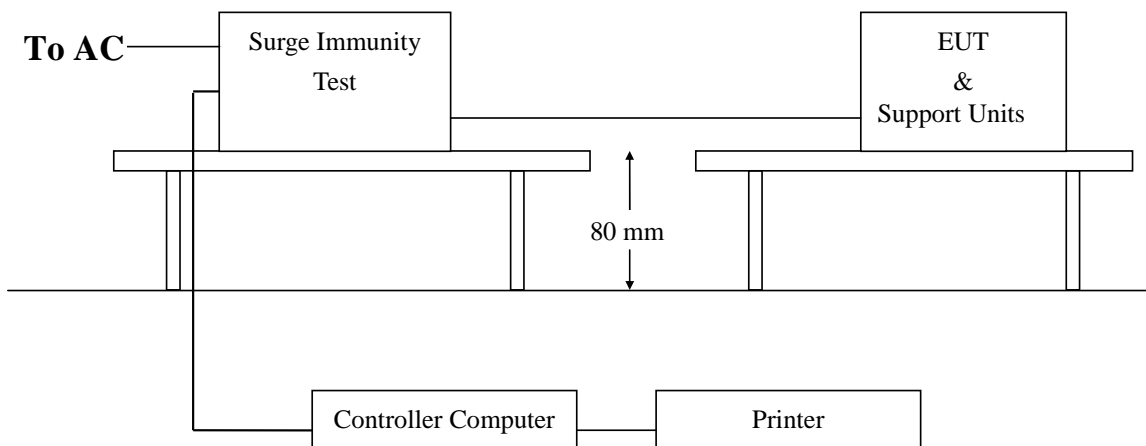
Observation: No any function degraded during the tests.

SECTION 6 EN 61000-4-5 (SURGE IMMUNITY)

SURGE IMMUNITY TEST

Port : Power Cord
Basic Standard : EN 61000-4-5
Requirements : $\pm 1\text{kV}$ (Line to Line)
 $\pm 2\text{kV}$ (Line to Ground)
Performance Criteria : B (Standard require)
Tested by : Jack Chen
Temperature : 26°C
Humidity : 45%

Block Diagram of Test Setup:





Test Procedure:

1. The Host PC (included EUT) and support units were located on a wooden table 0.8 m away from ground floor.
2. A test program was loaded and executed in Windows mode.
3. The data was sent to the screen of Monitor and filling the screen with upper case of "H" patterns.
4. The test program exercised related support units sequentially.
5. Repeating step 3 to 4 through the test.
6. Recording the test result as shown in following table.

Sformatowano: Wcięcie: Z lewej: 0 cm, Wsuniecie: 0,42 cm, Numerowanie + Poziom: 1 + Styl numeracji: 1, 2, 3, ... + Rozpoczniij od: 1 + Wyrównanie: Na lewo + Wyrównanie: 0 cm + Tabulator po: 0,42 cm + Wcięcie: 0,42 cm

Test conditions:

Voltage Waveform : 1.2/50 μ s
Current Waveform : 8/20 μ s
Polarity : Positive/Negative
Phase angle : 0°, 90°, 270°
Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1 + N	1	Positive	Capacitive	Pass
L1+PE	2	Positive	Capacitive	Pass
N + PE	2	Positive	Capacitive	Pass
L1+N	1	Negative	Capacitive	Pass
L1 + PE	2	Negative	Capacitive	Pass
N + PE	2	Negative	Capacitive	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS** ☐ **FAILED**

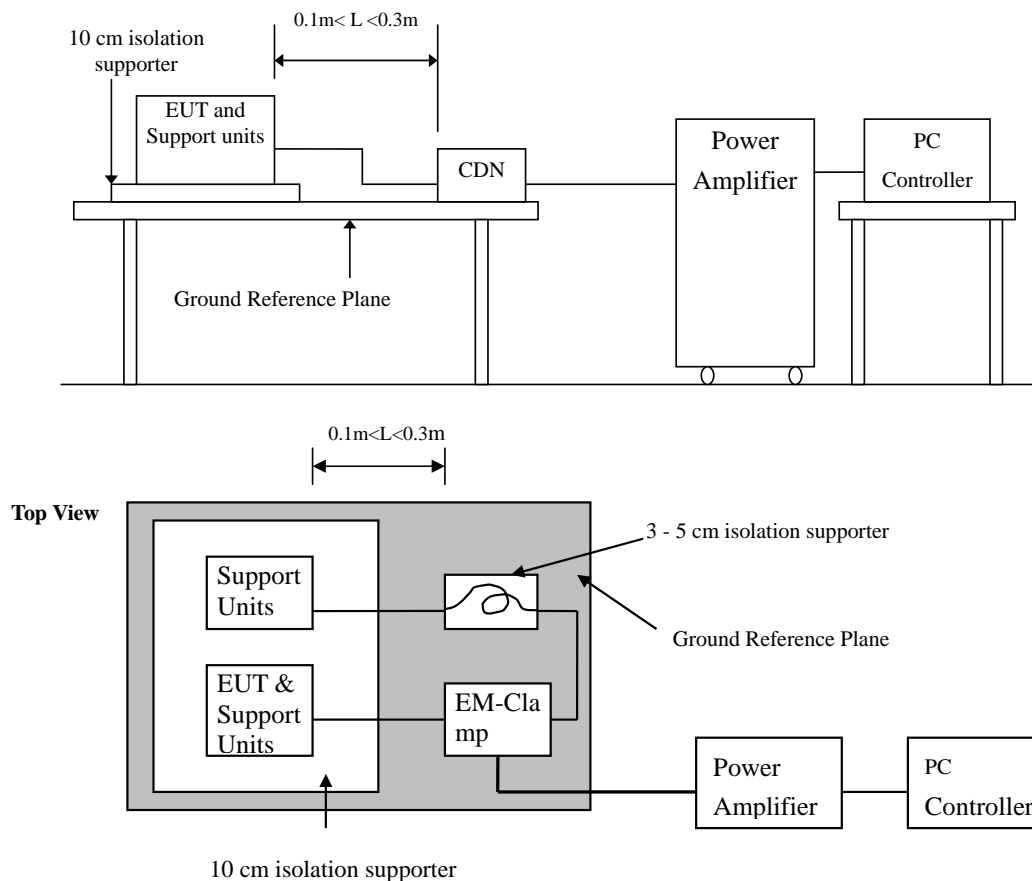
Observation: No any function degraded during the tests.



SECTION 7 EN 61000-4-6 (CONDUCTED DISTURBANCE/INDUCED BY RADIO-FREQUENCY FIELD)

Port : Power cord and Data Cable
Basic Standard : EN 61000-4-6
Requirements : 3V with modulated
Injection Method : CDN-M3 for Power Cordially,
 EM-Clamp for LAN Cable
Performance Criteria : A (Standard require)
Tested by : Jack Chen
Temperature : 25°C
Humidity : 59°C

Block Diagram of Test Setup:



Test Procedure:

1. The Host PC (included EUT) and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
2. A 'H' messages were displayed on Screen of Monitor.
3. Adjusting the monitoring camera to monitor the 'H' message as clear as possible.
4. Setting the testing parameters of CS test software per EN 61000-4-6.
5. Recording the test result in following table.

Test conditions:

Frequency Range : 0.15MHz-80MHz

Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

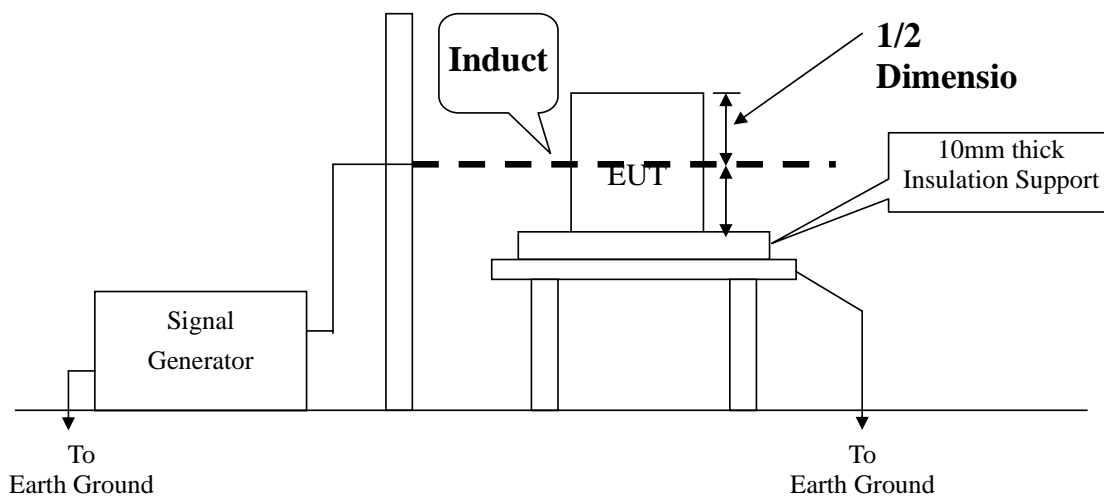
☒ **PASS** ☐ **FAILED**

Observation: No any function degraded during the tests.

SECTION 8 EN 61000-4-8 (POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST)

Port : Enclosure
Basic Standard : EN 61000-4-8
Requirements : 3 A/m
Performance Criteria : A (Standard Required)
Temperature : N/A
Humidity : N/A

Block Diagram of Test Setup:





Test Procedure:

Field Strength: 3A/m
Power Freq.: 50Hz
Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark

****Note:** Not applicable, because no any component can be influenced by power magnetic fields.

Performance & Result:

- ☐ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

**** Observation:** N/A

SECTION 9 EN 61000-4-11 (VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS)

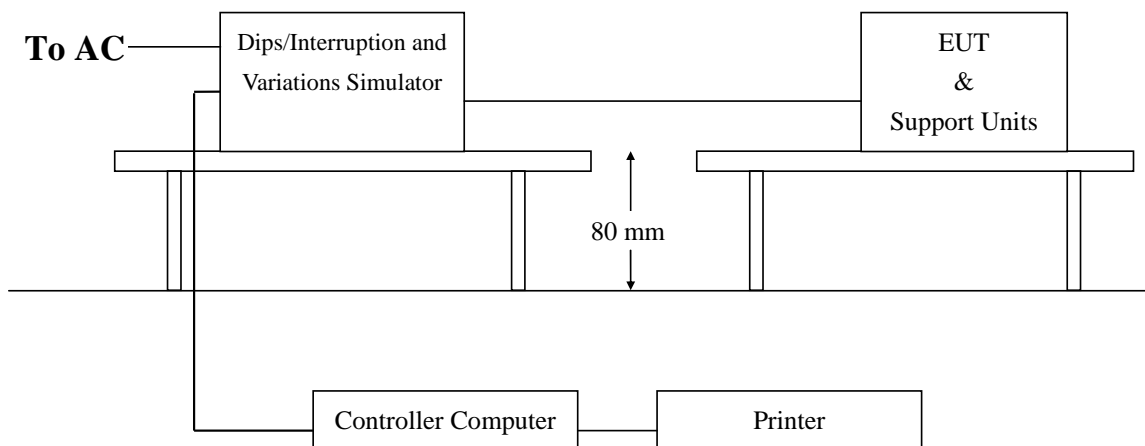
VOLTAGE DIPS / SHORT INTERRUPTIONS

Port : AC mains
Basic Standard : EN 61000-4-11 (1994)
Requirement : PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Test Level % U _T	Voltage Dip and Interrupt Reduction(%)	Duration (ms)	Performance Criteria
<0	>95	5000	C
70	30	10	B
40	60	100	C

Test Interval : Min. 10 sec.
Tested by : Jack Chen
Temperature : 24⁰C
Humidity : 52%

Block Diagram of Test Setup:





Test Procedure:

1. The Host PC (included EUT) and support units were located on a wooden table, 0.8 m away from ground floor.
2. A test program was loaded and executed in Windows mode.
3. The data was sent to the screen of Monitor and filling the screen with upper case of "H" patterns.
4. The test program exercised related support units sequentially.
5. Setting the parameter of tests and then Perform the test software of test simulator.
6. Repeating step 3 to 4 through the test.
7. Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10s minimum
(Between each test event)

Test Level % U _T	Voltage Dip and Interrupt Reduction(%)	Duration (ms)	Observation	Meet Performance Criteria
<0	>95	5000	EUT shot down but can be recovered by manual, as the events disappears	C
70	30	10	Normal	A
40	60	100	Normal	A

Performance & Result:

- Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS** ☐ **FAILED**



APPENDIX 1

PHOTOGRAPHS OF TEST SETUP

LINE CONDUCTED EMISSION TEST



RADIATED EMISSION TEST



POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST



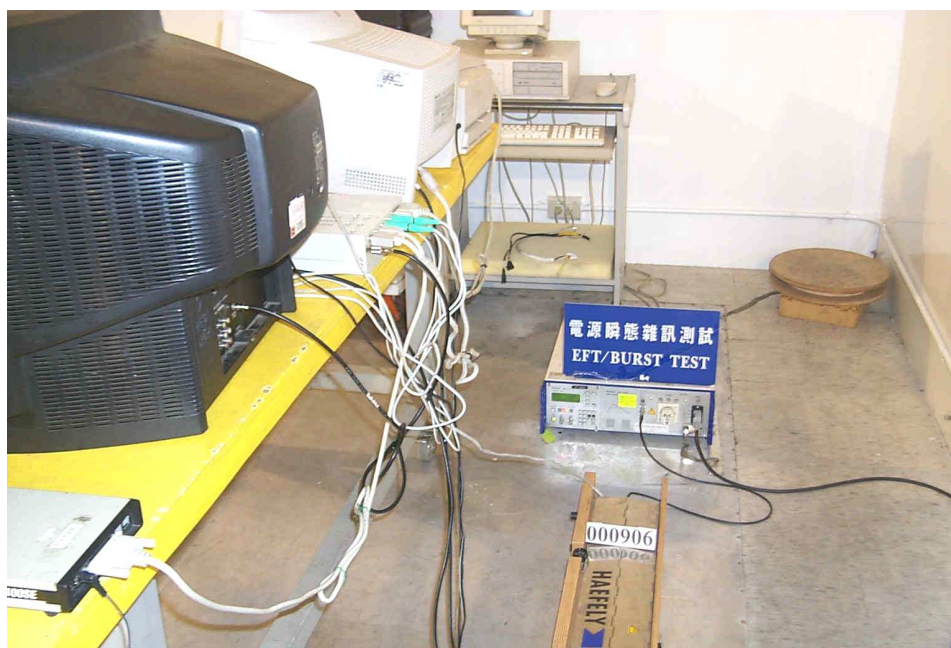
ELECTROSTATIC DISCHARGE TEST



RADIATED ELECTROMAGNETIC FIELD



FAST TRANSIENTS/BURST TEST



SURGE IMMUNITY TEST





CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



VOLTAGE DIP/INTERRUPTION TEST





APPENDIX 2

PHOTOGRAPHS OF EUT



